

C-V measurements in AC-LGADs

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For the SCIPP team



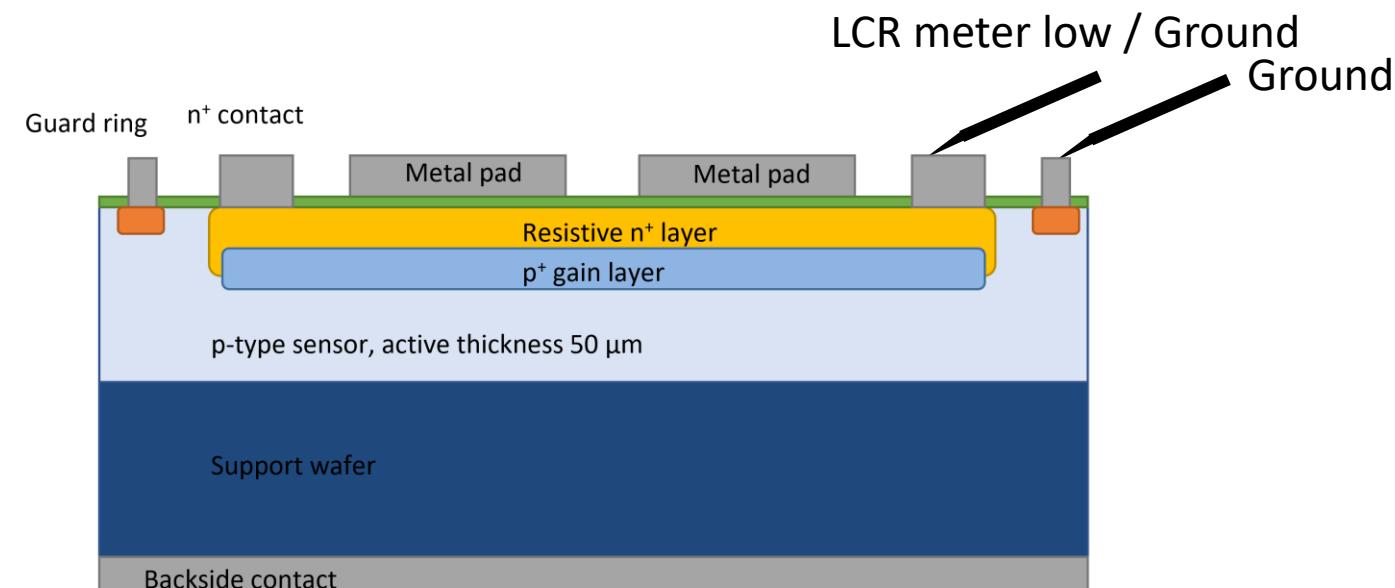
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Standard C-V measurement

“Conventional” C-V measurement configuration: sensor backplane to front side electrode

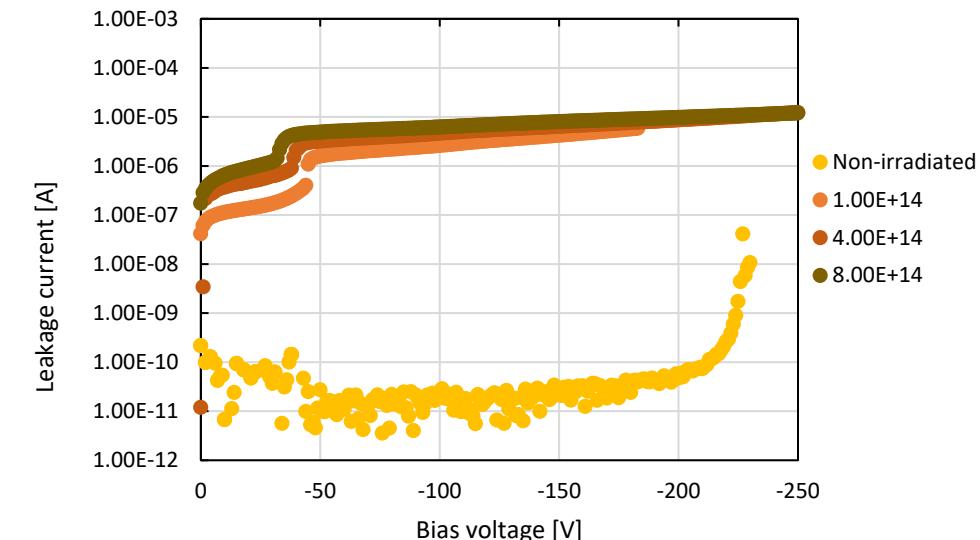
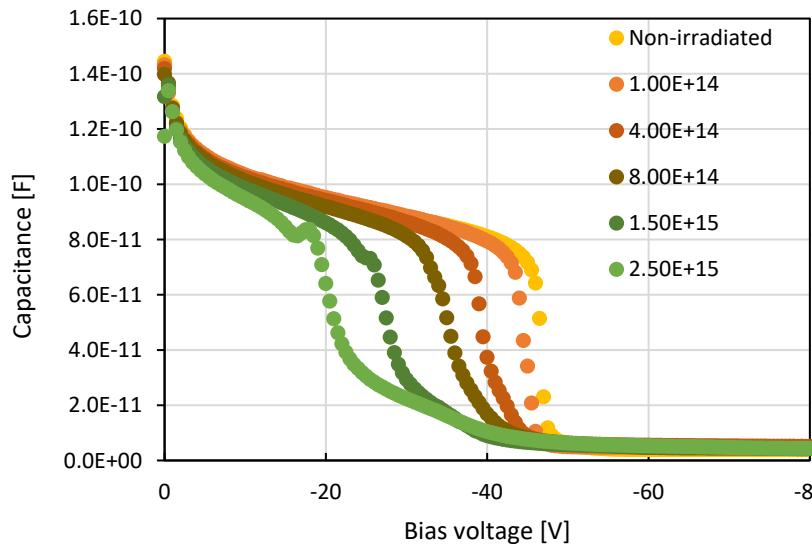
- In AC-LGADs, there is one shared n^+ layer with the DC contact – capacitance measured over the full sensor area
- Depending on area: **pF to 10s of pF**



Radiation damage

Irradiation has an impact on the bulk and on the gain layer, just like in other types of LGADs

- Bulk damage: increased leakage current and defect concentration – higher depletion voltage of the bulk volume
- Gain layer: “acceptor removal” – lower depletion voltage

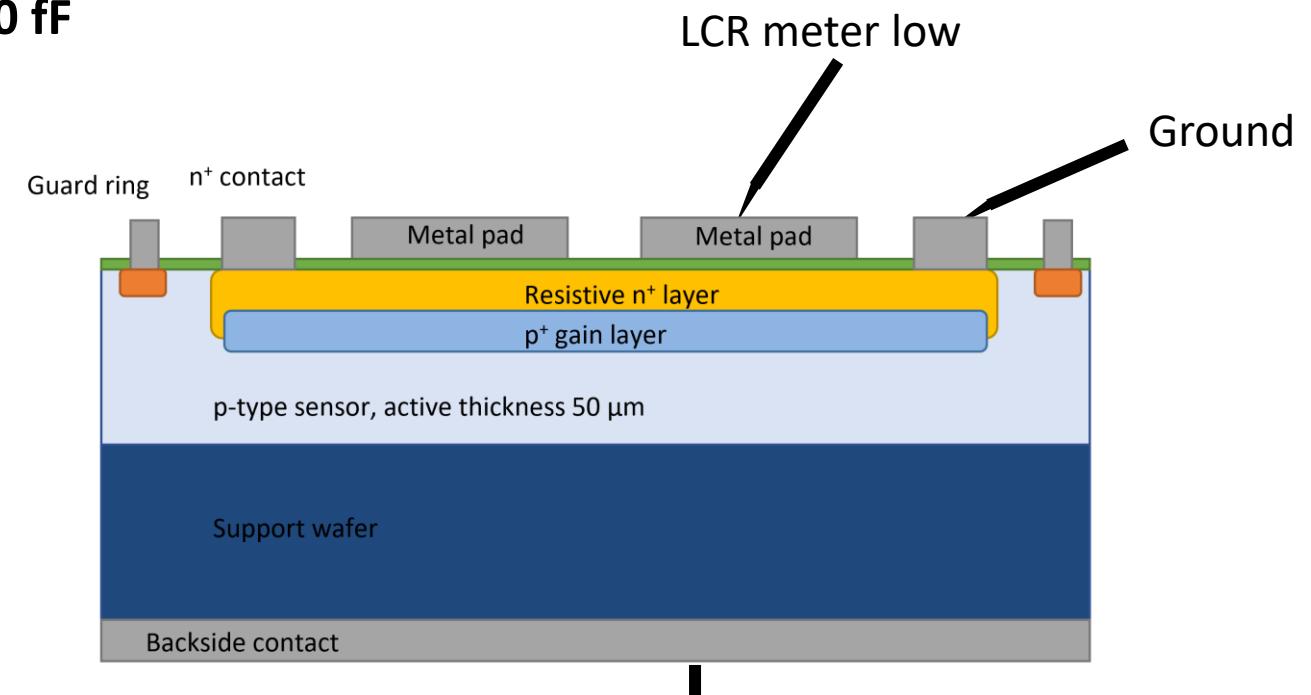
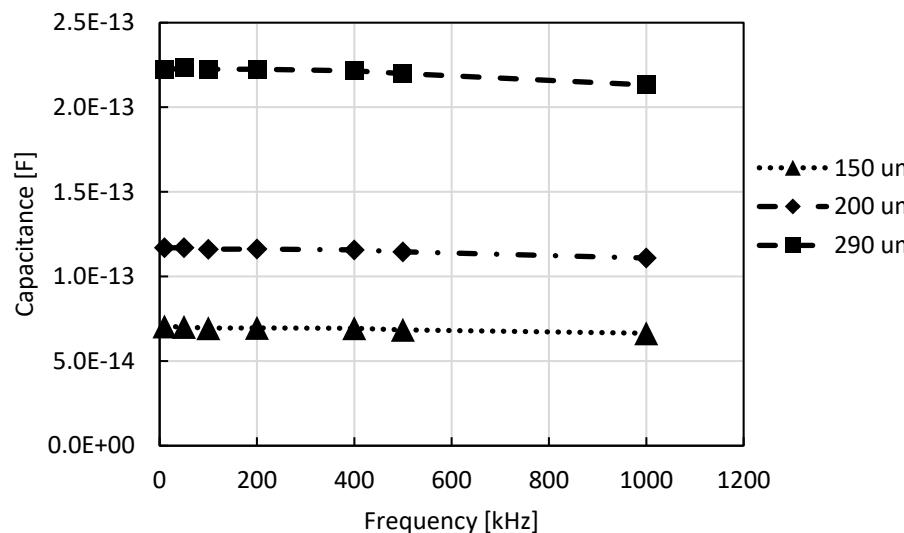


- Radiation levels of $\mathcal{O}(10^{14} \text{ cm}^{-2})$ as predicted for ePIC should not have a significant impact on sensor performance, but increase in leakage current needs to be considered

AC capacitance

Specific to AC-LGADs: measurement from backplane to individual AC metal pad

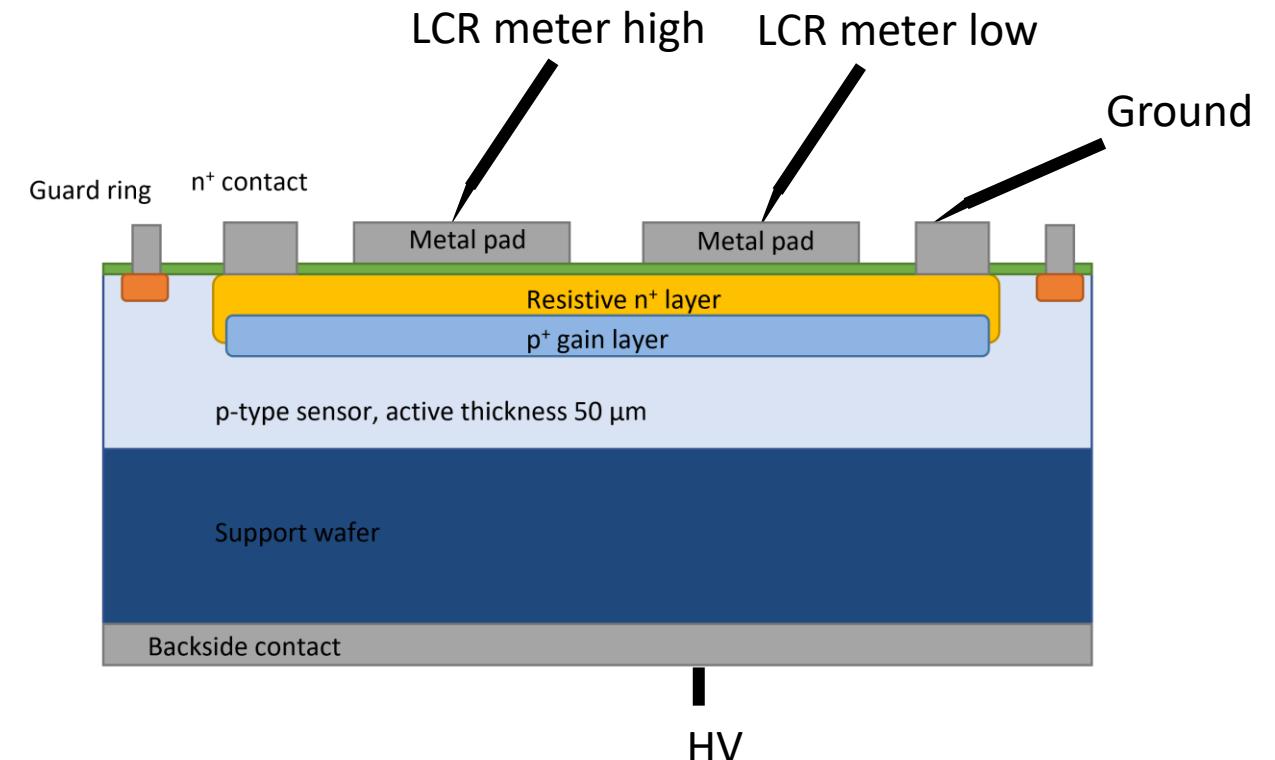
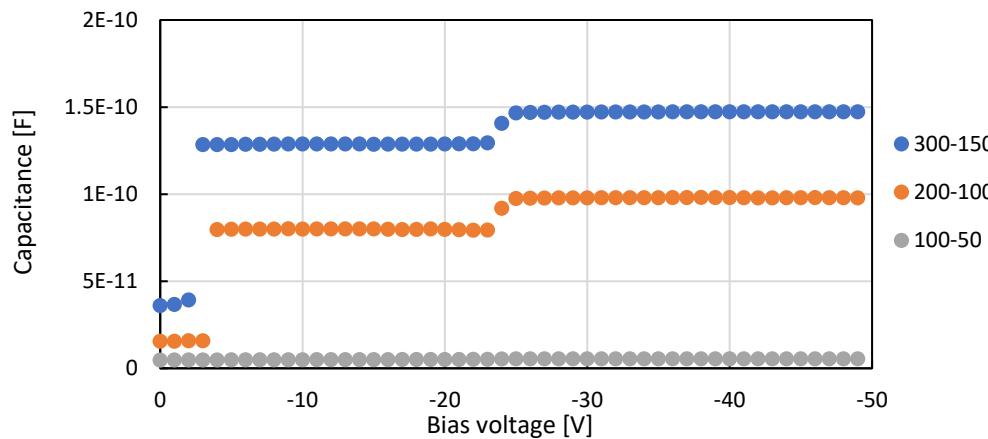
- Pad size affects the final capacitance values, since capacitance is directly proportional to the area
- Values after full depletion are relatively small compared to “regular” CV measurements: **for 150 μ m pads, < 100 fF**



Interpad capacitance

Interpad capacitance: between two AC metal pads, sensor biasing from backplane as usual, grounding to the n+ DC contact

- Depletion visible, frequency dependence before depletion – capacitance component through the bulk
- A factor in the observed higher signal sharing for longer strips



Reducing input capacitance by reducing metal?

E.g. cutting out the metal on strips, leaving a “frame” instead of a fully metallized strip, in FBK RSD2*

➤ Direct impact on electrode capacitance

J. Ott et al, AC-LGAD capacitances

